



Sheet 1 of 1 (7/29/04)

Form PTO-1449	ATTY. DOCKET NO. 4249-0113P	APPLICATION NO. 10/799,705
INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)		
APPLICANT CHI, Dongzhi et al.		GROUP 2822 Unassigned
FILING DATE March 15, 2004		

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	Kind	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
TYT	US 6,605,316	B1	2003-08-12	Visco et al.			
TYT	US 6,339,021	B1	2002-01-15	Tan et al.			
TYT	US 6,531,396	B1	2003-03-11	Chi et al.			
	US						
	US						
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	US						

FOREIGN PATENT DOCUMENTS

	Office	DOCUMENT NUMBER	Kind	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
								YES	NO
TYT	PCT	WO 02/47145	A1	2002-06-13	PCT				
TYT	PCT	WO 03/096407	A1	2003-11-20	PCT				
TYT	Japan	2002124487	A	2002-04-26	JAPAN			X	

OTHER DOCUMENTS

(Include Name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.)

EXAMINER /Thanh Tran/	DATE CONSIDERED 10/01/2006
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4249-0113P

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PTO/SB/08a/b (07-05)
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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete If Known	
				Application Number	10/799,705-Conf. #8968
				Filing Date	March 15, 2004
				First Named Inventor	Dongzhi CHI
				Art Unit	2822
				Examiner Name	T. Y. Tran
Sheet	1	of	1	Attorney Docket Number	4249-0113P

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
TYT	AA*	US-20020115262-A1	08-22-2002	Cabral et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ³
		Country Code ² -Number ⁴ -Kind Code ⁵ (if known)				
TYT	BA	JP-2003-213407-A	07-30-2003			✓

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NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ³	
TYT	CA	D. MANGELINCK et al., Applied Physics Letters, Vol. 75, No. 12, 20 September 1999, pp. 1736-1738		
TYT	CB	QU et al., Proceedings of the 6th International Conference on Solid-State and Integrated-Circuit Technology, IEEE, 2001, pp. 501-504		
TYT	CC	HOU et al., IEEE ELECTRON DEVICE LETTERS, Vol. 20, No. 11, November 1999, pp. 572-573		

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¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature	/Thanh Tran/	Date Considered	10/01/2006
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